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NATIONAL STANDARD OF THE

PEOPLE'S REPUBLIC OF CHINA

GB/T 17473.7-2022

Test methods of precious metals pastes used for microelectronics - Part 7: Determination of solderability and solder leaching resistance

(English Translation)

Issued by: State Administration for Market Regulation;
Standardization Administration of the PRC

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1 Foreword

GB/T 17473.7-2022 is issued by State Administration for Market Regulation; Standardization Administration of the PRC.

It replaces the earlier edition GB/T 17473.7-2008, GB/T 17473.7-1998.

It is one of 14 parts of the GB/T 17473 series.

2 Scope Preview

GB/T 17473.7-2022 carries no ICS number and no Chinese Standard Classification code.

This catalogue holds 75,626 other GB/T standards.

Of the 47,415 GB/T standards that do carry an ICS number, 3,437 (7%) fall under ICS 77, in the field of metallurgy.

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3 About this standard

Issued by: State Administration for Market Regulation; Standardization Administration of the PRC

English translation: about 15 pages (approximate)

4 Related standards

Other parts of this standard:

GB/T 17473-2025 - Performance test method for electronic pastes - Conductor pastes test

GB/T 17473.1-1998 - Test methods of precious metal pastes used for thick film microelectronics--Determination of solids content

GB/T 17473.1-2008 - Determination of solids content

GB/T 17473.2-1998 - Test methods of precious metal pastes used for thick film microelectronics--Determination of fineness

GB/T 17473.2-2008 - Determination of fineness

GB/T 17473.3-1998 - Test methods of precious metal pastes used for thick film microelectronics--Determination of sheet resistance

GB/T 17473.3-2008 - Determination of sheet resistance

GB/T 17473.4-1998 - Test methods of precious metal pastes used for thick film microelectronics--Determination of adhesion

GB/T 17473.4-2008 - Determination of adhesion

GB/T 17473.5-1998 - Test methods of precious metal pastes used for thick film microelectronics--Determination of viscosity

GB/T 17473.5-2008 - Determination of viscosity

GB/T 17473.6-1998 - Test methods of precious metal pastes used for thick-film microelectronics--Determination of resolution

GB/T 17473.6-2008 - Test methods of precious metal pastes used for microelectronics --Determination of resolution

Other editions:

GB/T 17473.7-2008 (earlier edition)

GB/T 17473.7-1998 (earlier edition)

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5 Classification and status

Prefix GB/T: recommended standard.

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